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Report of Executive Committee for 1977

The Report of the Executive Committee for 1977 has been published in *Acta Crystallographica*, Section A [*Acta Cryst.* (1978), A34, 1031–1046]. It reports on the meetings and publications of the Union, the work of its Commissions, and the work of bodies not belonging to the Union on which the Union is represented.

Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the Executive Secretary of the International Union of Crystallography (J. N. King, International Union of Crystallography, 13 White Friars, Chester CH1 1NZ, England).

The Warren Award

The Fourth Bertram Eugene Warren Diffraction Physics Award will be presented at the meeting of the American Crystallographic Association in Boston, Massachusetts in August, 1979.

This award was established by students and friends of Professor Warren on the occasion of his retirement from the Massachusetts Institute of Technology. It is to be given for an important recent contribution to the physics of solids or liquids using X-ray, neutron, or electron diffraction techniques. This includes work such as elastic or inelastic scattering studies of imperfections in crystals, or studies of liquids or amorphous materials, or developments in diffraction theory appropriate to such problems, to give a few examples; it does not include crystal structure determinations. Work that is to be eligible for this award must have been published between 1 July 1972 and 30 June 1978. There are no restrictions as to age, experience, or nationality of recipients. The award consists of a certificate and \$1000 and is to be given every three years.

The following committee has been appointed to select the 1979 award recipient: D. Chipman, S. Cargill, and J. B. Cohen, Chairman.

The selection committee will welcome suggestions for possible recipients by 1 January 1979 from any interested persons. Suggestions should be addressed to Professor J. B. Cohen, Department of Materials Science and Engineering, The Technological Institute, Northwestern University, Evanston, Illinois 60201, USA.

Book Reviews

Works intended for notice in this column should be sent direct to the Book-Review Editor (J. H. Robertson, School of Chemistry, University of Leeds, Leeds LS2 9JT, England). As far as practicable books will be reviewed in a country different from that of publication.

Diffraction from materials. By L. H. Schwartz and J. B. Cohen. Pp. xv+558. New York: Academic Press, 1977. Price US \$27.50, £19.95.

This book contains a thorough introduction to diffraction methods by means of X-rays, neutrons, and electrons. It is written for students in the senior or first grad-

uate year at a university. The chapters are (1) *Principles of Crystallography*; (2) *Geometrical Representation of Crystals*; (3) *The Nature of Diffraction*; (4) *Properties of Radiation Useful for Studying the Structure of Materials*; (5) *Recording the Diffraction Pattern*; (6) *Determination of Crystal Structures*; (7) *What Else Can We Learn from Diffraction Experiments besides the Average Structure*; (8) *The Dynamical Theory of Diffraction*. Going through them the reader very soon accepts that this book has evolved over a fifteen-year period. Nearly all the questions, which students and also people experienced in the field of diffraction normally ask, are explained. Each chapter culminates in a reference list and in 20 to 25 problems. The answers to most of the problems are given in an appendix. X-ray generators are only mentioned, the excellent rotating-anode generators being referred to only in a footnote. However, one finds a good review on counters in this book including position-sensitive counters, solid-state counters and also the method of nondispersive diffraction by means of a multichannel analyser. The authors have succeeded in revealing the mutual limitations in the application of electron, X-ray, and neutron diffraction. The pioneer of X-ray fluorescence analysis and of chemical analysis by absorption, R. Glocker, should perhaps receive some mention in the second edition.

The very essential point *Determination of the Power of the Direct Beam in X-ray Diffraction* is treated in an appendix (10 pages). The thorough treatment of the different aspects is kept to a high standard up to the end of Chapter 6 on p. 356, but one finds in Chapter 7 only certain very fundamental principles, for example of small-angle scattering work or of diffraction from liquids and amorphous solids.

Since the determination of residual stresses and of textures is also treated in a very brief way elsewhere in the text, there is a challenge to expand Chapter 7. In Chapter 8, B. Batterman and H. Cole have collaborated with L. H. Schwartz and J. B. Cohen to present the review on dynamical diffraction (73 pp.).

It must be hoped that this excellent text book will find a wide distribution and will thus open the way for further fruitful applications of X-ray, electron, and neutron diffraction methods.

S. STEEB

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Crystal growth 1977. Edited by *R. L. Parker, A. A. Chernov, G. W. Cullen and J. B. Mullin.* Pp. xvi + 662. North Holland, 1977. Price Dfl 350.00, US \$ 152.25.

In this *Proceedings Volume* of the *Journal of Crystal Growth*, refereed manuscripts are presented from both invited and contributed speakers at the 5th International Conference on Crystal Growth, held at the Massachusetts Institute of Technology, USA, during July 1977. The volume contains some 92 manuscripts from the 265 talks presented at the Conference and is therefore not a full record but it constitutes a good representation of the content of the Conference. The volume covers all

the major aspects of crystal growth and is divided into thirteen clear groupings concerned with theory and nucleation, vapour growth and epitaxy, solution growth and crystallization, organic and biological crystals, flux growth, liquid-phase epitaxy, basic studies of melt growth, melt growth of high-melting-point materials such as oxides, fluid dynamics and microgravity, growth techniques, special materials and new developments, eutectics and alloys and, finally, defects. These sections commence with useful review papers which up-date the relevant topics. Distributed amongst the various sections are many useful papers upon the crystal growth of modern electronic device materials such as silicon, the III-V compounds, magnetic garnets, lasers, piezoelectric compounds and infrared window materials. Computer simulation of crystal growth and efforts to automate appropriate parts of crystal growth processes also feature prominently. An understanding of crystal defects and their control is always important to crystal-growth scientists and this aspect is well covered. The links now being forged between crystallization processes and biological materials are also apparent in a number of papers.

In summary, this is a useful addition to the crystal-growth literature as a reference volume for current trends but for a full appreciation of the Conference to which it relates, it must be examined in conjunction with the regular editions of the *Journal of Crystal Growth* where some of the other papers presented are due to appear.

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